

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Prior Application: T. YAMANAKA et al  
USSN 09/825,921  
Filed: April 5, 2001

Group Art Unit: 2814  
Examiner: H. Pham  
For: SEMICONDUCTOR MEMORY DEVICE AND  
METHOD OF MANUFACTURING THE SAME

INFORMATION DISCLOSURE STATEMENT

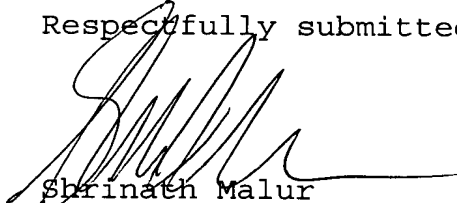
Commissioner of Patents  
Mail Stop Patent Application  
Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure, Applicants inform the Examiner of the documents cited during prosecution of the parent application, U.S. Serial No. 09/825,921.

Applicants request the Examiner to initial and return a copy of the attached PTO-1449 form to indicate that the references have been considered.

Respectfully submitted,

  
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Date: September 12, 2003

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. ASA-804-04		SERIAL NO.	
<b>LIST OF DOCUMENTS CITED BY APPLICANT</b> <i>(Use several sheets if necessary)</i>				APPLICANT T. YAMANAKA et al			
				FILING DATE September 12, 2003		GROUP	
<b>U.S. PATENT DOCUMENTS</b>							
* EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE <i>(If Appropriate)</i>
	AA	5,564,245	08/1997	Allen, Gregory Lee			
	AB	6,103,566	08/200	Tamaru et al			
	AC	5,365,095	11/1994	Shono et al			
	AD	6,140705	10/2000	Liu			
	AE	5,728,595	03/1998	Fukase			
	AF	5,796,136	08/1998	Shinkawata			
	AG	5,767,541	06/1998	Hanagasaki			
	AH	5,536,672	07/1996	Miller et al			
	AI	6,407,420	06/2002	Yamanaka et al			
	AJ						
	AK						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATIO YES NO
	AL	7-142597	6/2/95	Japanese Laid-Open Patent			<input type="checkbox"/> <input type="checkbox"/>
	AM	5-299601	11/12/93	Japanese Laid-Open Patent			<input type="checkbox"/> <input type="checkbox"/>
	AN	8-181290	7/12/96	Japanese Laid-Open Patent			<input type="checkbox"/> <input type="checkbox"/>
	AO	8-56152	2/16/96	Japanese Laid-Open Patent			<input type="checkbox"/> <input type="checkbox"/>
	AP	6-45552	2/18/94	Japanese Laid-Open Patent			<input type="checkbox"/> <input type="checkbox"/>
<b>OTHER DOCUMENTS</b> <i>(Including Author, Title, Date, Pertinent Pages, etc.)</i>							
	AR	IEEE INT., ELECTRON DEVICES MEETING, Technical Digest, Dec. 1994, pp. 927-929.					
	AS						
	AT						
EXAMINER				DATE CONSIDERED			
<small>* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form next communication to applicant.</small>							

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	AJ					
	AK					

**FOREIGN PATENT DOCUMENTS**

DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATIO YES	NO
AL 62-48062	3/2/87	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>
AM 62-128168	6/10/87	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>
AN 6-151751	5/31/94	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>
AO 3-263371	11/22/91	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>
AP 07-297364	11/1995	Japan (with English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, etc.)

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AT		

EXAMINER \_\_\_\_\_ DATE CONSIDERED \_\_\_\_\_

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